



STANDARD SPECIFICATION

产品规格书

客户 Customer:			
客户料号 Customer P/N NO.:			
产品描述 Product Description:	3225-OSC	30.000MHZ	±10PPM
HX-C 料号 P/N. NO.:	3Y030000VP		

客户批准 Customer Approval:

审核	批准
Checked	APPROVED

(请批准后回签一份 PLEASE RETURN A COPY WITH APPROVAL)

拟制	审 核	批 准
DESIGNER	CHECK	APPROVED
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REVISION RECORD

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1. 石英晶体参数规格 QUARTZ CRYSTAL UNIT SPECIFICATION

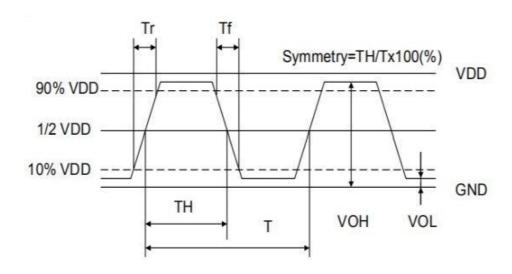
电气特性 Electrical Characteristics

	也 (付任 Electrical Cil	iaracte	1131103				
		符号		电气特性规格			
	项目	Symb	El	ectrical	Specifica	tion	备注
	Item	ol	下限	中心	上限	单位	Notes
			Min.	Тур.	Max.	Units	
1	标准频率 Nominal Frequency	FL		30.000		MHz	
2	震荡模式 Oscillation Mode	-	F	undament	al	-	
3	频率偏差 Frequency Tolerance	FT	-10	-	10	ppm	At 25°C±°C
4	温度频差 Equivalent Series Resistance	TC	-30	-	30	ppm	
5	工作温度 Operating Temperature		-45	-	85	°C	
6	储存温度范围 Storage temperature range	T_stg	-55	-	125	°C	
7	老化率 Aging rate	F_age		±2		ppm	First year
8	供电电压 For the pressure	Vdd		1.8 ~ 3.3		V	±10%
9	电流 current	lcc			7.0	mA	
10	上升,下降时间 Rise, fall time			5		Ns	10%~90% Level
11	输出波形 Output waveform			CMOS			
12	占空比 Duty ratio	TH/T	45		55	%	
13	输出负载 The output load	CL		15		pF	
14	三态 Output Enable		70%Vdd			V	Pin 1 Tri-state
15	三态 Output Disable				30%Vdd	V	Till Thestate

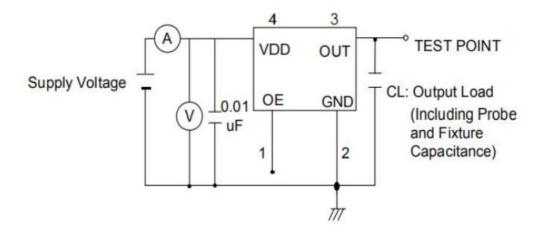




2. CMOS负载输出波形 LOAD OUTPUT WAVEFORM



3. CMOS 负载电路测试 LOAD CIRCUT TEST

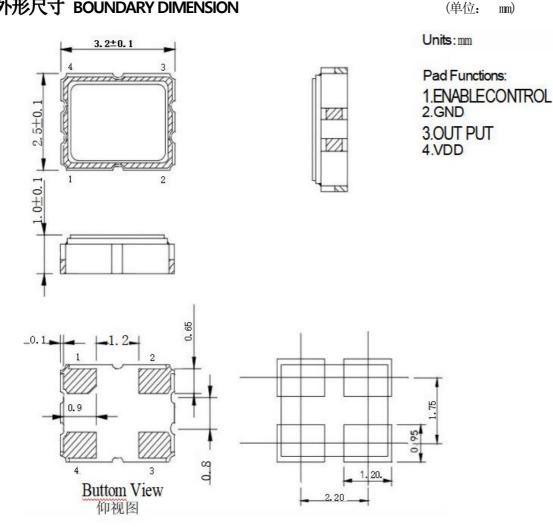






mm)

4. 外形尺寸 BOUNDARY DIMENSION



Notes:PIN 1 connected to Vdd or floating,the product is working properly;connected to GND,stops working.

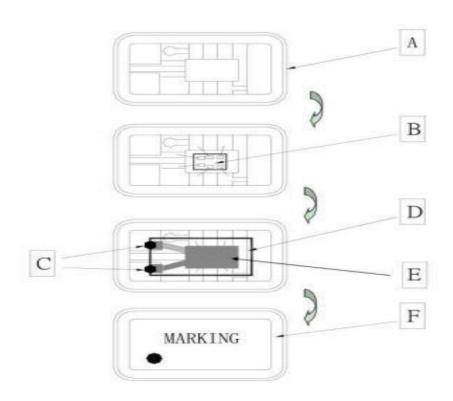
5. 印字







6. 内部结构图 INSIDE STRUCTURE



组件	上及名称	材质	组件及名称		材质
A	基座	$A1_2O_3$	D	晶片	SiO_2
В	芯片	硅	Е	电极	Cr+Ag
С	导电胶	Ag + 硅树脂	F	上盖	Kovar



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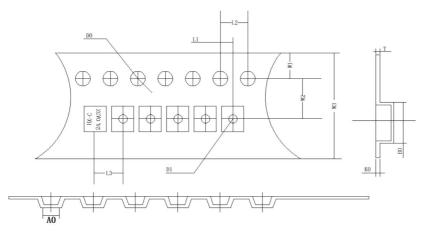


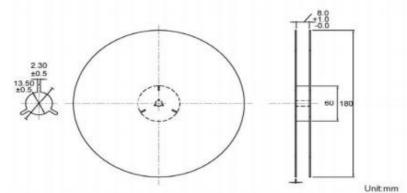


7. 编带包装 BRAID PACKAGING

(单位: mm)

1. 载带与编带盘尺寸

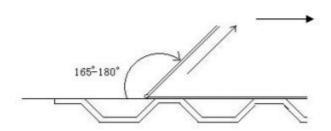




L1	2.00 ± 0.1
L2	4.00±0.1
L3	4.00±0.1
DO	1.50 ± 0.1
D1	1.00 ± 0.1
WO	8.30 ± 0.2
W1	1.75 ± 0.1
W2	3 50±0 1
W3	8 00±0 1
AO	2.72 ± 0.1
В0	3.46 ± 0.1
КО	1.00 ± 0.1
T	0.22 ± 0.05

2. 剥离方式见下图,强度: 20g-100g

牵引方向

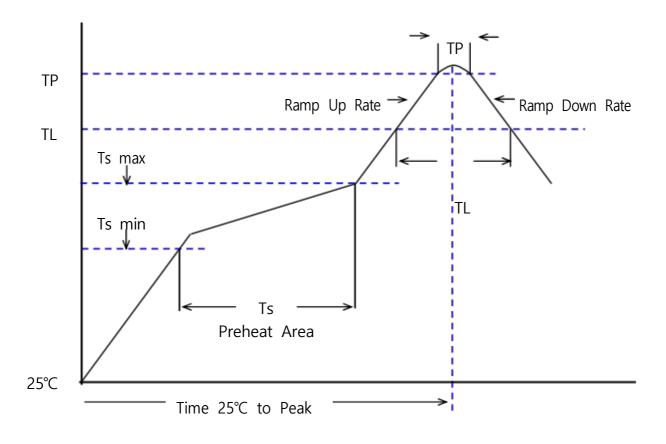






8. 回流焊温度曲线 REFLOW PROFILES

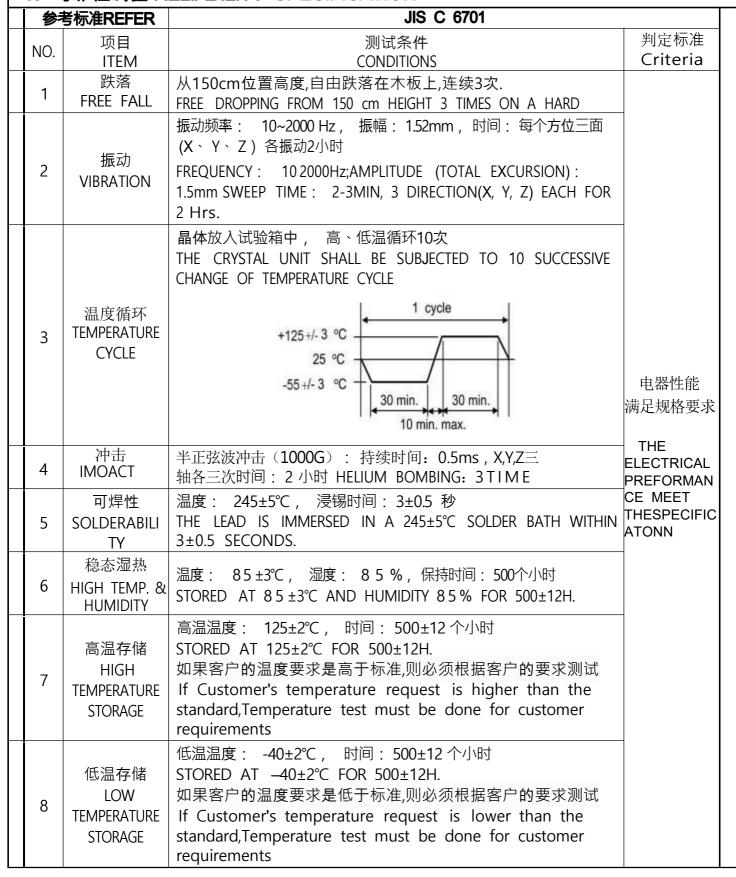
参考标准 REFER: JEDEC J-STD-020D	
Profiles Feature	Pb-Free Assembly
Preheat/Soak	
Temperature Min (Ts min)	150℃
Temperature Max (Ts max)	200°C
Time (Ts) from (Ts min to Ts max)	60-120 seconds
Ramp-up rate (TL to TP)	3°C/second max.
Liquidous temperature (TL)	217℃
Time (TL) maintained above TL	60-150 seconds
Peak/Classification Temperature (TP)	260±5°C
Time within 5℃ of actual Peak	
Temperature (TP)	20~40 seconds
Ramp-down rate (TP to TL)	6°C/second max.
Time 25 °C to peak temperature	8 minutes max.
Suggest reflow times	3 Times max







9. 可靠性试验 RELIABILITY SPECIFICATION







10. 包装数量 NUMBER OF PACKAGES

类型 TYPE	尺寸 SIZE	数量 NUMBER
包装盒 Packaging	180*20*180	3000pcs
包装箱 Packing cases	240*200*200	30000pcs

★ 各注:

- 1. 以上可靠性项目为我司常规测试项目,若客户对产品有跌落,冲击,碰撞以及涉及到超声 波焊接工艺的需求,请将贵司的需求反馈给我司,我司会对该产品的可靠性项目进行更新。 2. 客户端在对晶体加热后,为了保证频率的准确性,建议将晶体充分冷却后再进行相关测试。 3. 该产品符合公司环保标准要求。
- 1. The above reliability items are routine test items of our company. If the customer has requirements on the products including drop, impact, collision and ultrasonic wave welding process, please feedback your requirements to our company, and we will update the reliability items of this product. 2. In order to ensure the accuracy of frequency, it is recommended to fully cool the crystal after heating it on the client. 3. The product meets the company's environmental standards.